

<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10009579	DE LEIJ ET AL.
	Examiner Qian Ph.D., Celine X	Art Unit 1636

Notes	Date	Examiner
Search updated.	9/15/06	CQ
U.S. Patent and Trademark Office		Part of Paper No.: